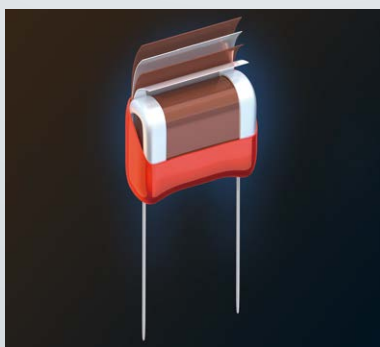
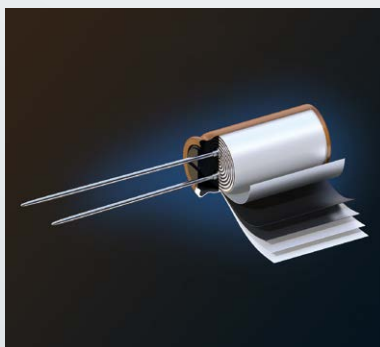
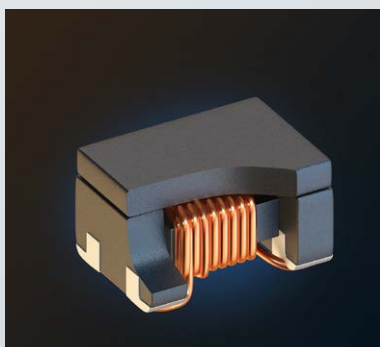
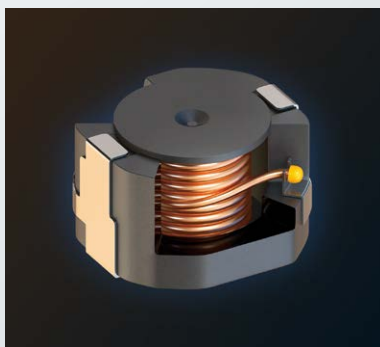
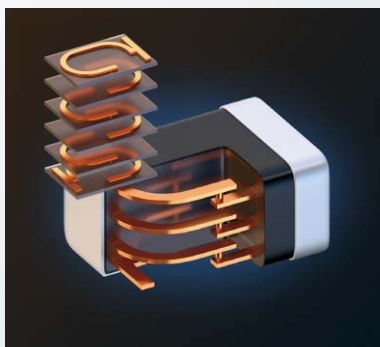


Electrical measurement in electronic component performance evaluation and quality testing

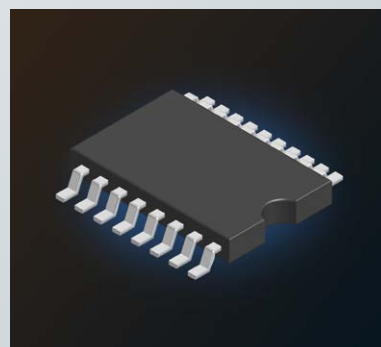
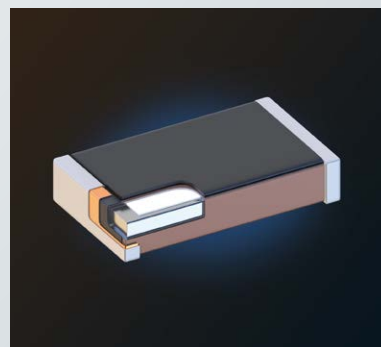
Capacitors



Inductors



Resistors





Increasingly computerized automobiles



Information and communication between cars (V2X)



Smart factories



Automated shipping services



Data centers that support high-capacity communication



Smart houses for efficient use of electricity



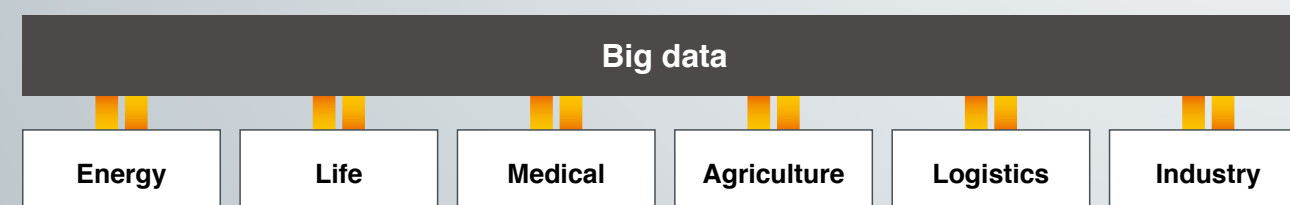
Increasingly sophisticated devices



Growing crops using drones

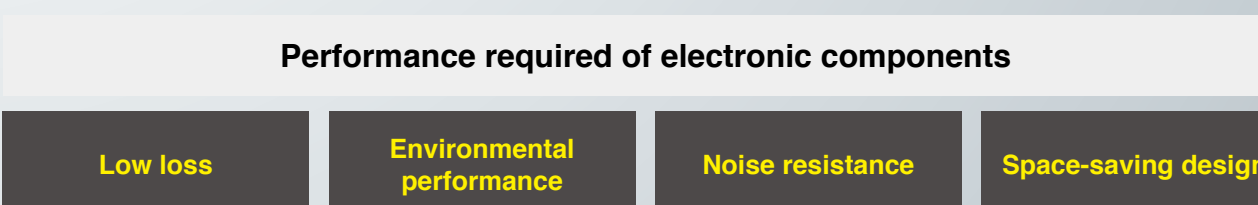
Moving towards a sustainable society with digital technology and 5G

Trends are accelerating towards connecting devices with information and using energy efficiently. Innovations in a variety of core functions of society are taking place due to the combination of fast, high-bandwidth data communications based on 5G networks and advanced digital technologies.



Electronic components that make possible advanced digital technologies

All digital technologies are supported by highly reliable electric circuits. The performance of electronic components exerts a major influence on the operation of the electric circuits they comprise. In recent days, ensuring electronic components deliver a high level of performance is an essential part of satisfying market requirements.

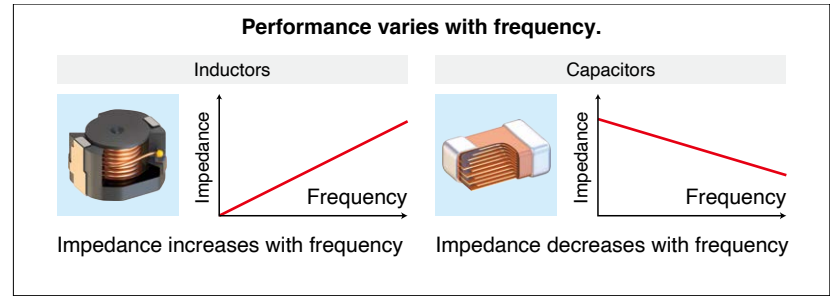


Measuring the performance of electronic components

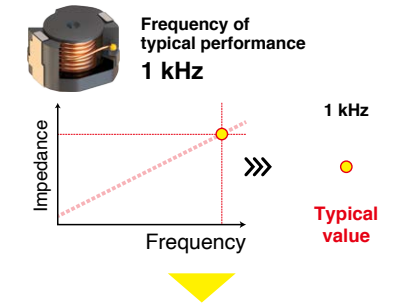
Electric circuits operate properly when electronic components perform as designed. It is possible to design highly reliable circuits by measuring electronic components to accurately assess their performance.

Assessing the performance of electronic components

Electricity frequency affects the performance of electronic components to a significant degree. That makes it important to check the performance of electronic components at the frequencies at which they will actually be used.



Observing representative performance



LCR Meters

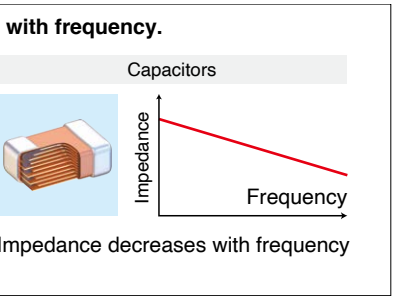
Check the performance of electronic components while applying electricity of particular frequencies

Model	Measurement frequency
IM3533	1 MHz to 200 kHz

Model	Measurement frequency
IM3536	4 Hz to 8 MHz

Assessing changes in the performance by frequency

Frequency affects the performance of electronic components to a significant degree. That's why it's important to check how the performance of electronic components changes as the frequency changes.



Impedance Analyzers

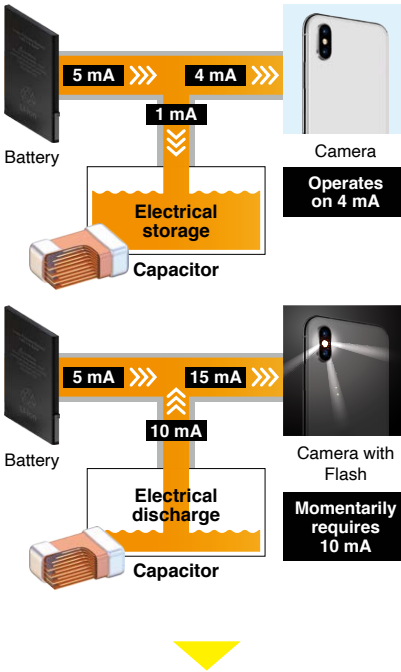
Check the characteristics of electronic components while varying the frequency and signal magnitude.

Model	Measurement frequency
IM7580A	1 MHz to 300 MHz
IM7581	100 kHz to 300 MHz
IM7583	1 MHz to 600 MHz
IM7585	1 MHz to 1.3 GHz
IM7587	1 MHz to 3 GHz

Model	Measurement frequency
IM3570	4 Hz to 5 MHz

Measuring capacitors

Capacitors store and discharge electricity in circuits. The ability to store electricity in this manner is known as capacitance. Various types of capacitors are available, and it's necessary to choose the type that best suits your application.



C Meters

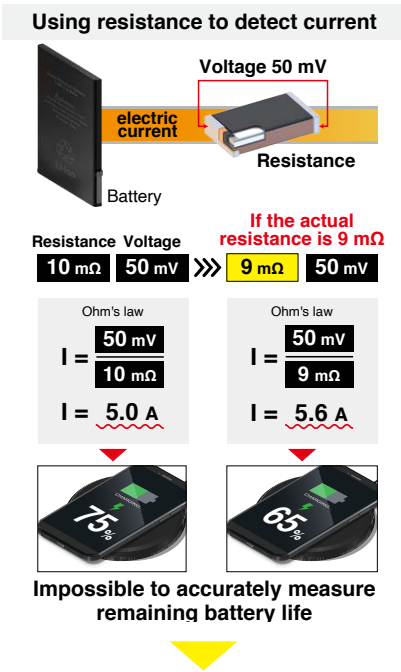
Measure the capacitance of capacitors.

Measurement of large C values	
Model	Capacitance measurement range
3504-40	0.9400 pF to 20.0000 mF
3504-50	0.9400 pF to 20.0000 mF
3504-60	0.9400 pF to 20.0000 mF

Measurement of low C values	
Model	Capacitance measurement range
3506-10	0.001 fF to 15.0000 µF

Measuring resistors

Resistors regulate the amount of electricity flowing in a circuit, and they're used to detect the magnitude of currents. By accurately assessing resistors' resistance value and embedding them in circuits, you can regulate and detect current with a high degree of precision.



Resistance meters

Measure resistance with a high degree of precision.

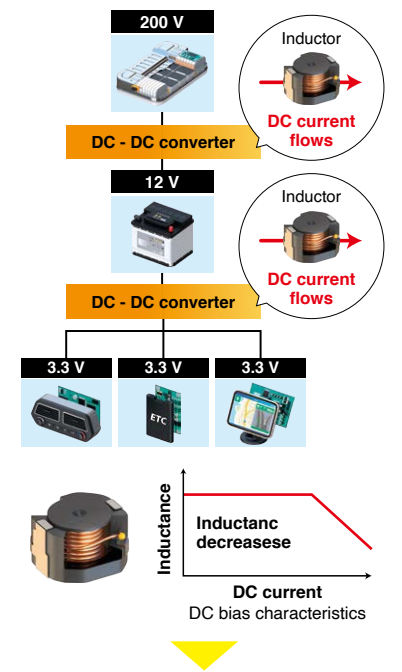
Low Rdc measurement	
Model	Resistance measurement range
RM3543	0.00000 mΩ to 1200.000 Ω

High Rdc measurement	
Model	Resistance measurement range
RM3542A	0.0000 mΩ to 120.0000 MΩ*1

Multichannel pass/fail measurement	
Model	Resistance measurement range
RM3545-02	0.00000 mΩ to 1200.0 MΩ*1

Checking DC bias characteristics

When a DC current flows to a coil, the circuit's inductance may vary. The resulting tendencies are known as DC bias characteristics.



DC Bias Current Unit LCR Meter

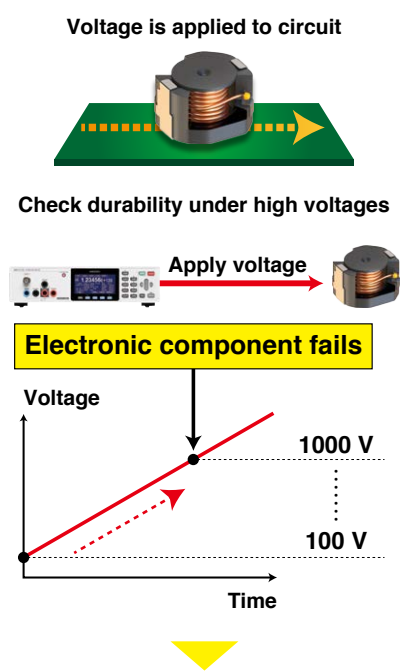
Superpose a DC current from an external power source onto the measurement signal to measure the DC bias characteristics.

Connect between a test fixture and instrument. Maximum applied current: DC 2 A	
Model	Measurement frequency
9269-10	40 Hz to 2 MHz

Model	Measurement frequency
IM3536	4 Hz to 8 MHz

Testing durability

Applying a voltage above a certain level to an electronic component will damage the component and cause the device to fail. That's why it's important to check whether the component can withstand the voltage applied by the designed circuit.



Super Megohm Meters Insulation/withstanding Testers

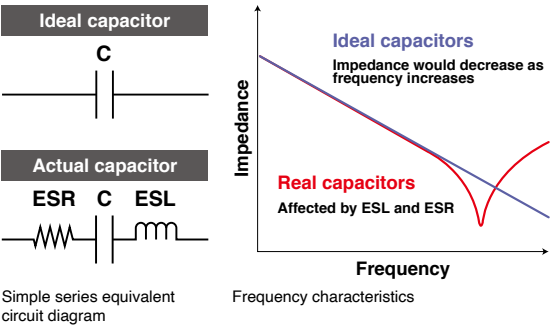
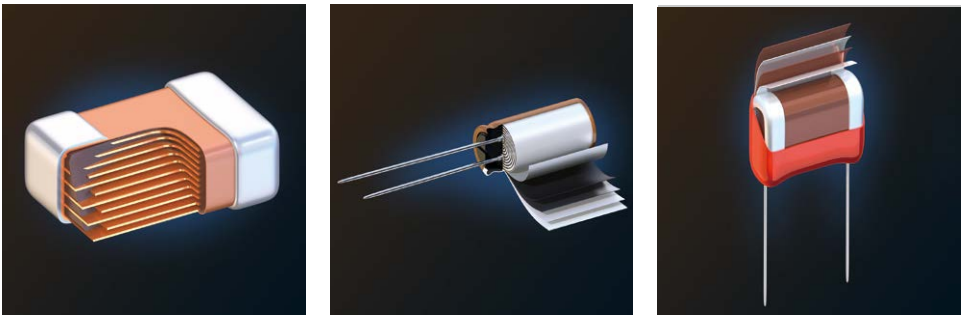
Check an electronic component's durability by applying a gradually increasing voltage to it.

Insulation resistance measurement	
Model	Test voltage (DC)
SM7110	0.1 V to 1000.0 V
SM7120	0.1 V to 2000.0 V

Model	Test voltage (DC)
SM7420	Varies with external power source

Withstand voltage tester	
Model	Test voltage (AC/DC)
3153	0.2 kV to 5.00 kV

Capacitor




Equivalent series resistance (ESR) and equivalent series inductance (ESL)

An ideal capacitor would be an element that has only capacitance (C). In reality, however, capacitors have ESR (resistance called Equivalent Series Resistance) caused by losses from the dielectric substance, electrodes, and other factors, as well as parasitic ESL (inductance called Equivalent Series Inductance) caused by electrodes, lead wires, and other factors.

Loss coefficient D (tan δ)

The loss coefficient D (tan δ) expresses the power loss of a capacitor. Smaller values indicate less power loss, and therefore higher-quality capacitors.

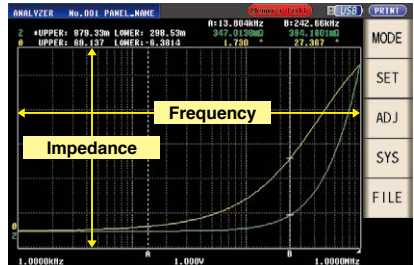


IM3570
Measurement frequency: 4 Hz to 5 MHz
Measurement parameters:
Z, Y, θ, Rs, Rp, X, Rdc, G, B, Cs, Cp, Ls, Lp, D, Q

Impedance Analyzer

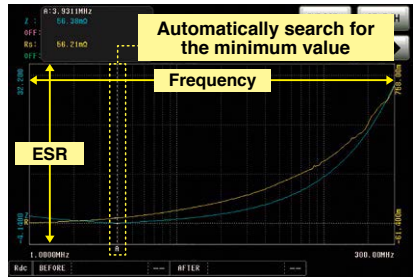
Checking frequency characteristics

Check frequency characteristics by making measurements while sweeping through a range of frequencies. The IM3570 can perform frequency sweep measurement for two parameters simultaneously.




Checking behavior at high frequencies

Check characteristics to determine how parameter values vary by making measurements while sweeping through a range of measurement frequencies.




Evaluating power loss

ESR (Equivalent Series Resistance) is a cause of power loss. Identify the frequency associated with minimum ESR by measuring ESR while sweeping through a range of measurement frequencies.



IM3533
Measurement frequency: 1 mHz to 200 kHz
Measurement parameters:
Z, Y, θ, Rs, Rp, X, Rdc, G, B, Cs, Cp, Ls, Lp, D, Q, N, M, ΔL, T



IM3536
Measurement frequency: 4 Hz to 8 MHz
Measurement parameters:
Z, Y, θ, Rs, Rp, X, Rdc, G, B, Cs, Cp, Ls, Lp, D, e, σ

LCR Meters

Measuring C, D, and ESR

The IM3533 and IM3536 can continuously measure C, D, and ESR, which describe the basic performance of capacitors. The instruments can also compare measured values to user-specified references and display judgment results.

C-D measurement: 120 Hz

Cs **590.328μF** IN

D **0.03561** IN

Vac 6.655mV
Iac 2.960mA

Judging measurement results

The instruments compare measured values to user-specified references and display the judgment results.

Continuous measurement under varying test conditions

ESR measurement: 100 kHz

Rs **20.6121mΩ** HI

Vac 1.945mV
Iac 93.47mA

Setting the measurement signal level

Open-circuit voltage (V) mode
Set the voltage produced by the instrument's signal source


Constant-voltage (CV) mode
Set the voltage applied to the DUT

Constant-current (CC) mode*
Set the current that flows to the DUT

This mode is used when measuring devices that exhibit current dependency, for example inductors with cores

*Not available for the 3504 series.

The panel save function lets you save measurement conditions (for example, "measure C and D at 120 Hz" or "measure ESR at 100 kHz"), while the continuous measurement function lets you perform continuous measurement under varying measurement conditions.



3504-40, 3504-50, 3504-60
Measurement frequency: 120 Hz or 1 kHz
Measurement parameters: C, D
Capacitance measurement range:
0.9400 pF to 20.0000 mF

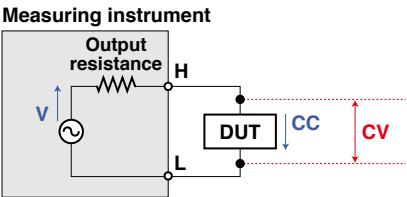
C Meter

Measuring the C values of high-capacity capacitors

The C values of high-capacity MLCCs that use dielectric substances with high permittivity vary significantly with the applied voltage. The constant-voltage (CV) mode provided by the 3504 series lets you make measurements while applying a defined voltage as the measurement signal.

C measurement range	0.9400 pF to 20.0000 mF
Measurement voltage (open-circuit voltage)	100 mV*, 500 mV, 1 V
Measurement voltage (constant voltage)	100 mV*, 500 mV, 1 V
Measurement frequency	120 Hz, 1 kHz, 1 MHz

*3504-60 only



Setting the measurement signal level

Open-circuit voltage (V) mode
Set the voltage produced by the instrument's signal source


Constant-voltage (CV) mode
Set the voltage applied to the DUT

This mode is used when measuring components that exhibit voltage dependency, for example a high-permittivity MLCC

Constant-current (CC) mode*
Set the current that flows to the DUT

This mode is used when measuring devices that exhibit current dependency, for example inductors with cores

*Not available for the 3504 series.



3506-10
Measurement frequency: 1 kHz or 1 MHz
Measurement parameters: C, D, Q
Capacitance measurement range:
0.001 fF to 15.0000 μF

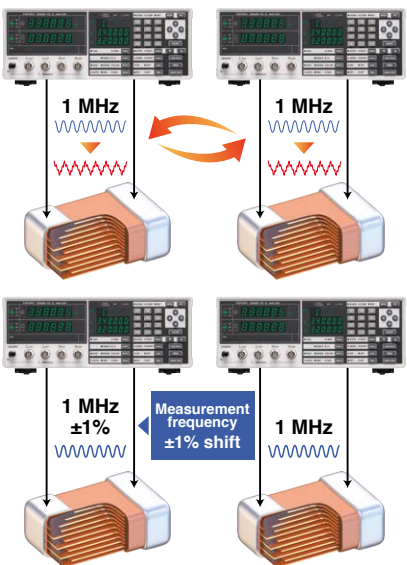
C Meter

Measuring the C values of low-capacitance capacitors


The 3506-10 provides optimal ranges for low-capacitance C measurement.

C measurement range	0.000 fF to 15.0000 μF
Measurement voltage (open-circuit voltage)	500 mV, 1 V
Measurement frequency	1 kHz, 1 MHz


Interference when using multiple instruments




Measurement frequency interference occurs when multiple instruments are used at the same time on a production line. The measurement frequency shift



SM7110
Test voltage: 0.1 V to 1000.0 V



SM7120
Test voltage: 0.1 V to 2000.0 V



SM7420
Test voltage: Varies with external power source

Super Megohm Meters

Evaluating insulation resistance while applying a high voltage

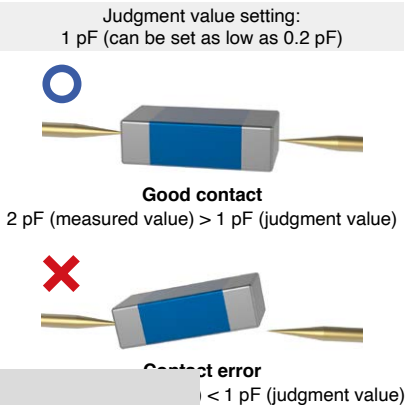
The SM7110 and SM7120 can test insulation at voltages of up to 1000 V or 2000 V, respectively. The SM7420 can shorten insulation test cycle time by using an external power source across 4 channels.

Check the insulation of the capacitor by applying a voltage to it

Determining the measurement probe contact

The instrument can determine the contact status by measuring capacitance and comparing the result to a previously-set judgment value.

Judgment value setting:
1 pF (can be set as low as 0.2 pF)





3153
Test voltage (AC): 0.2 kV to 5.00 kV
Test voltage (DC): 0.2 kV to 5.00 kV

Insulation/withstanding Testers

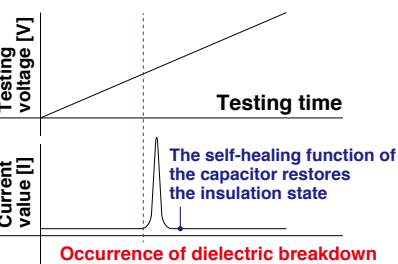
Withstand voltage testing with AC or DC test voltages

The 3153 can automatically perform continuous AC or DC withstand voltage testing. The test voltage's rising and falling times can be set separately. You can check for faulty voltage values by gradually increasing the test voltage.

Test voltage
0.20 kV to 5.00 kV AC 0.20 kV to 5.00 kV DC
Test time
0.1 sec. to 99.9 sec.

Testing the self-healing functions of film capacitors

The self-healing function can be tested by gradually increasing the test voltage.

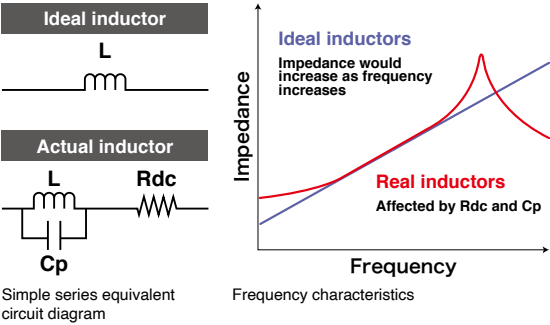
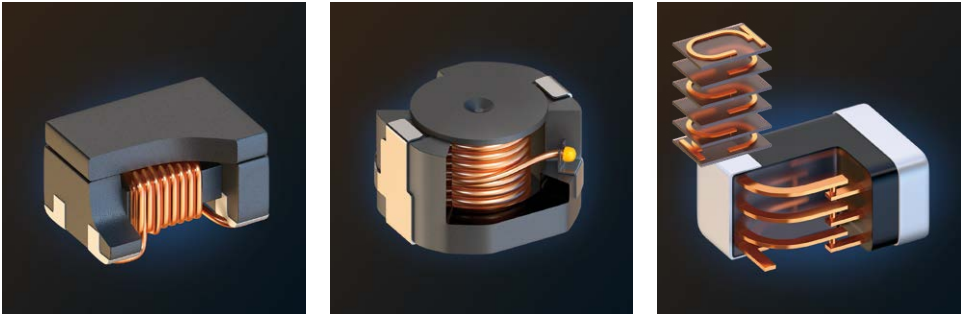


Self-healing function:
Function that instantaneously restores the insulated state, even if the insulation breakdown occurs

Film capacitors are primarily used in power supply circuits to smooth the supply of power. Because the integrity of the insulation in capacitors has a significant impact on component safety, standards such as IEC 60384-14 have been defined to address the risk of fire and electric shock hazards.

IEC 60384-14: An international standard that outlines safety performance such as the voltage endurance and flame resistance of capacitors connected to commercial power supplies from the perspective of preventing hazards caused by electric leaks, including fire and electric shock.

Inductors



DC resistance Rdc (DCR)
An ideal coil would be an element that has only inductance (L). In reality however, coils have resistance from the winding wire and coil, Rdc, as well as capacitance between the winding wires, Cp.

Loss coefficient Q (quality factor)
Q is an important quality indicator for high-frequency coils. Larger values indicate less power loss and therefore higher-quality coils.

IM7580s Series
Measurement parameters:
Z, Y, θ , Rs, Rp, X, G, B, Cs, Cp, Ls, Lp, D, Q

IM3570
Measurement parameters:
Z, Y, θ , Rs, Rp, X, Rdc, G, B, Cs, Cp, Ls, Lp, D, Q

Impedance Analyzers

Checking frequency characteristics

Check frequency characteristics by making measurements while sweeping through a range of frequencies. The IM7580s series and IM3570 can simultaneously perform sweep measurement for two or four parameters, respectively.

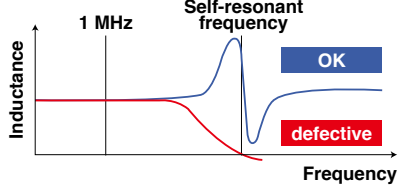
Model	Measurement frequency
IM3570	4 Hz to 5 MHz
IM7580A	1 MHz to 300 MHz
IM7581	100 kHz to 300 MHz
IM7583	1 MHz to 600 MHz
IM7585	1 MHz to 1.3 GHz
IM7587	1 MHz to 3 GHz

Generating pass and fail judgments based on user-defined values
Generate pass and fail judgments based on whether coils satisfy required specifications.

Area judgment
User-specified judgment threshold of the full frequency sweep

Spot judgment
User-specified judgment thresholds of user-specified frequencies

Detecting minuscule shorts between winding wires and the core
Checking inductance frequency characteristics up to the vicinity of the self-resonant frequency can reveal differences between non-defective parts and parts with shorts.



IM3533
Measurement frequency: 1 mHz to 200 kHz
Measurement parameters:
Z, Y, θ , Rs, Rp, X, Rdc, G, B, Cs, Cp, Ls, Lp, D, Q, N, M, ΔL , T

IM3536
Measurement frequency: 4 Hz to 8 MHz
Measurement parameters:
Z, Y, θ , Rs, Rp, X, Rdc, G, B, Cs, Cp, Ls, Lp, D, ϵ , σ

LCR Meters

Measuring L, Q, and Rdc

The IM3533 and IM3536 can make measurements while switching between AC and DC signals. The instruments can measure L and Q using an AC signal and Rdc using a DC signal.

L and Q measurement: 1 kHz

Rdc measurement: DC

9269-10
Measurement frequency: 40 Hz to 2 MHz
Maximum applied current at frequency: 2 A DC
Connect between fixture and instrument.

IM3536
Measurement frequency: 4 Hz to 8 MHz
Measurement parameters:
Z, Y, θ , Rs, Rp, X, Rdc, G, B, Cs, Cp, Ls, Lp, D, ϵ , σ

LCR Meters

Measuring DC bias

DC bias can affect L values. The IM3536 and 9269-10 can be used with an external power source to superimpose a DC current on the measurement signal and measure a coil's L value.

DC bias characteristics
At 100 kHz

DC current superimposed on the measurement signal

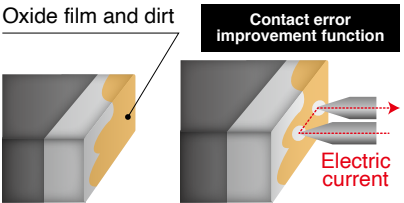
RM3542A
Resistance measurement range:
0.0000 m Ω to 120.0000 M Ω (LOW POWER OFF)*
0.000 m Ω to 1200.000 Ω (LOW POWER ON)*
Measurement current: 100 mA DC to 100 nA DC

Resistance Meters

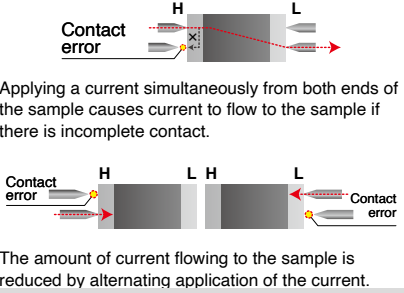
Measuring the Rdc of ferrite beads at high speed

The RM3542A can measure the Rdc of ferrite beads in as little as 0.9 ms.

Increasing productivity by addressing contact errors
Oxide film and dirt between the probes and sample can result in incomplete contact, causing a contact error. The RM3542A addresses this issue by applying a current to destroy oxide film and dirt.



Anticipating changes in ferrite bead characteristics
Applying a current to ferrite (a magnetic material) affects the material's characteristics. The amount of current flowing to the sample can be reduced by alternately applying a current to destroy oxide films and dirt.

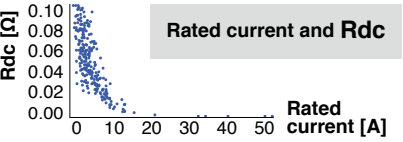


RM3545
Resistance measurement range:
0.00000 m Ω to 1200.0 M Ω
Measurement current: 1 A DC to 100 nA DC

Resistance Meters

Measuring low Rdc at high accuracy

Low-Rdc inductors are becoming more common as a way to reduce energy loss. The RM3545 can measure low Rdc at high accuracy and high resolution.



High-accuracy measurement

Range	Basic accuracy	Measurement current
10 m Ω	$\pm 0.060\%$ rdg. + 0.001% f.s.	1 A
100 m Ω	$\pm 0.014\%$ rdg. + 0.001% f.s.	1 A, 100 mA
1000 m Ω	$\pm 0.008\%$ rdg. + 0.002% f.s.	100 mA, 10 mA
10 Ω	$\pm 0.008\%$ rdg. + 0.001% f.s.	10 mA, 1 mA
100 Ω	$\pm 0.007\%$ rdg. + 0.001% f.s.	10 mA, 1 mA
1000 Ω	$\pm 0.006\%$ rdg. + 0.001% f.s.	1 mA
10 k Ω	$\pm 0.007\%$ rdg. + 0.001% f.s.	1 mA
100 k Ω	$\pm 0.007\%$ rdg. + 0.001% f.s.	100 μ A
1000 k Ω	$\pm 0.008\%$ rdg. + 0.001% f.s.	10 μ A
10 M Ω	$\pm 0.030\%$ rdg. + 0.001% f.s.	1 μ A
100 M Ω	$\pm 0.200\%$ rdg. + 0.001% f.s.	100 nA, 1 μ A or less
1000 M Ω	$\pm 1.00\%$ rdg. + 0.02% f.s.	1 μ A or less

High resolution

Range	Resolution	Max. display
10 m Ω	10 n Ω	12,000.00 m Ω
100 m Ω	100 n Ω	120,000.0 m Ω
1000 m Ω	1 $\mu\Omega$	1200,000 m Ω
10 Ω	10 $\mu\Omega$	12,000.00 Ω
100 Ω	100 $\mu\Omega$	120,000.0 Ω
1000 Ω	1 m Ω	1200,000 Ω
10 k Ω	10 m Ω	12,000.00 k Ω
100 k Ω	100 m Ω	120,000.0 k Ω
1000 k Ω	1 Ω	1200,000 k Ω
10 M Ω	10 Ω	12,000.00 M Ω
100 M Ω	10 k Ω	120,000.0 M Ω
1000 M Ω	100 k Ω	1200.0 M Ω

SM7110
Test voltage: 0.1 V to 1000.0 V

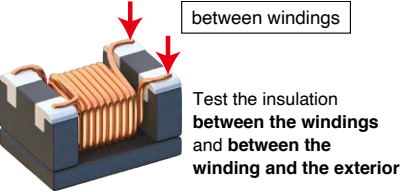
SM7120
Test voltage: 0.1 V to 2000.0 V

SM7420
Test voltage: varies with external power source

Super Megohm Meters

Evaluating insulation resistance while applying a high voltage

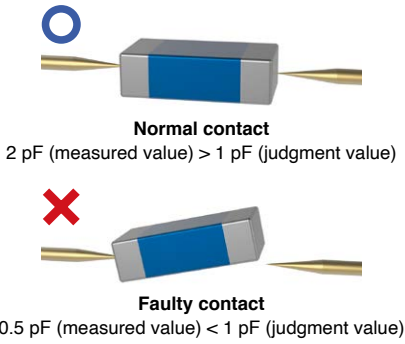
The SM7110 and SM7120 can test insulation at voltages of up to 1000 V or 2000 V, respectively. The SM7420 can test insulation across 4 channels when used with an external power source to shorten test cycle times.



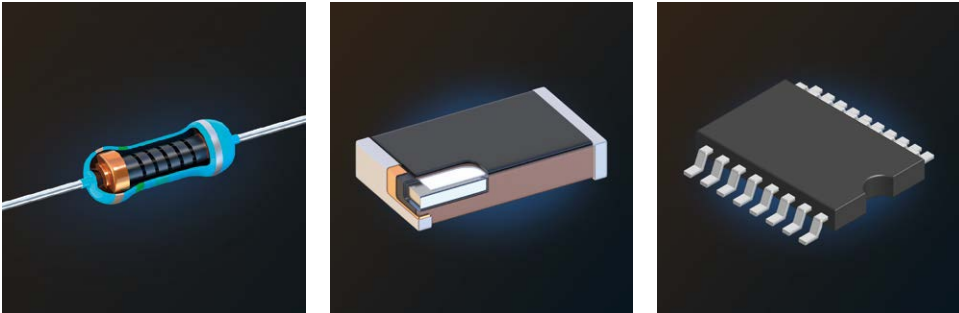
SM7110	SM7120	SM7420
Number of channels		
1 ch	1 ch	4 ch
Test voltage		
0.1 V to 1000.0 V	0.1 V to 2000.0 V	-


Determining the measurement probe contact
The status of contact is determined by measuring capacitance and comparing the result to a previously-set judgment value.

When judgment value is 1 pF (can be set as low as 0.2 pF)



Resistors



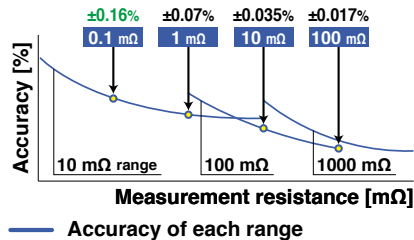


RM3543
Resistance measurement range:
0.00000 mΩ to 1200.000 Ω
Measurement current: 1 A DC to 1 mA DC

Resistance Meters

Measuring low Rdc with high accuracy

The RM3543 can perform measurements with high accuracy (0.1 mΩ ±0.16%) and high resolution (0.01 μΩ).




High-accuracy measurement

Range	Basic accuracy	Measurement current
10 mΩ	±0.060% rdg. +0.001% f.s.*1	1 A
100 mΩ	±0.060% rdg. +0.001% f.s.*2	1 A, 100 mA
1000 mΩ	±0.012% rdg. +0.001% f.s.	100 mA
10 Ω	±0.008% rdg. +0.001% f.s.	10 mA
100 Ω	±0.007% rdg. +0.001% f.s.	10 mA
1000 Ω	±0.006% rdg. +0.001% f.s.	1 mA

*1: With averaging enabled and set to 16 or more iterations
*2: Measurement current: 1 A

High resolution

Range	Resolution	Max. display
10 mΩ	10 nΩ	12.000 00 mΩ
100 mΩ	100 nΩ	120.000 0 mΩ
1000 mΩ	1 μΩ	1200.000 mΩ
10 Ω	10 μΩ	12.000 00 Ω
100 Ω	100 μΩ	120.000 0 Ω
1000 Ω	1 mΩ	1200.000 Ω



RM3542A
Resistance measurement range:
0.0000 mΩ to 120.0000 MΩ
Measurement current: 100 mA DC to 100 nA DC

Special specifications are available to measure resistances of about 100 MΩ with high accuracy (less than 500 ppm)

Resistance Meters

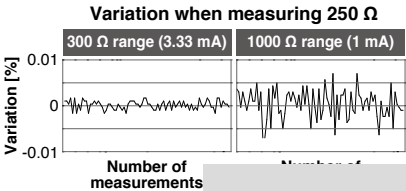
Measuring high Rdc with high accuracy

The RM3542A includes a 100 MΩ range that allows accurate measurement of high Rdc.

Range	Basic accuracy	Measurement current
100 mΩ	±0.015% rdg. + 0.002% f.s.	100 mA
1000 mΩ	±0.012% rdg. + 0.001% f.s.	100 mA
3 Ω	±0.012% rdg. + 0.001% f.s.	33.3 mA
10 Ω	±0.008% rdg. + 0.001% f.s.	10 mA
100 Ω	±0.007% rdg. + 0.001% f.s.	10 mA
300 Ω	±0.007% rdg. + 0.001% f.s.	3.33 mA
1000 Ω	±0.006% rdg. + 0.001% f.s.	1 mA
10 kΩ	±0.007% rdg. + 0.001% f.s.	1 mA
30 kΩ	±0.007% rdg. + 0.001% f.s.	333 μA
100 kΩ	±0.007% rdg. + 0.001% f.s.	100 μA
300 kΩ	±0.007% rdg. + 0.001% f.s.	33.3 μA
1000 kΩ	±0.008% rdg. + 0.001% f.s.	10 μA
3 MΩ	±0.008% rdg. + 0.001% f.s.	3.33 μA
10 MΩ	±0.030% rdg. + 0.004% f.s.	1 μA
30 MΩ	±0.030% rdg. + 0.010% f.s.	333 nA
100 MΩ	±0.100% rdg + 0.020% f.s.	100 nA

Using the SLOW measurement speed setting with the LOW POWER mode off

High repeatability
The instrument applies an appropriate measurement current based on the resistance value of the resistor under measurement. The instrument delivers high repeatability and is ideally suited for use in shipping inspections of resistors with low nominal value tolerances.





Z3003
4-terminal measurement: 10 ch
2-terminal measurement: 21 ch




RM3545-02
Resistance measurement range:
0.00000 mΩ to 1200.0 MΩ
Measurement current: 1 A DC to 100 nA DC


Resistance Meters

Generating pass and fail judgments for multiple channels


The Z3003 (sold separately) can be installed on the RM3545-02 to increase the number of measurement channels. Additionally, measurement results for channel 1 can be used as reference values to generate pass and fail judgments based on the measurement results for subsequent channels.



4-terminal measurement: 10 ch
2-terminal measurement: 21 ch



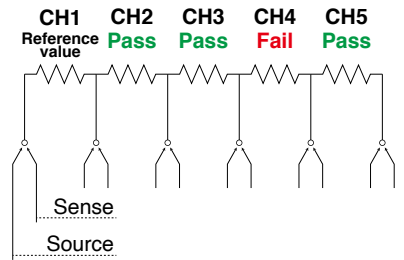
4-terminal measurement: 10 ch
2-terminal measurement: 21 ch



Z3003: Two units can be installed

Generating pass and fail judgments for network resistance

Network components are composite components that group multiple resistors together into a single package. One resistor in the network resistance can be used as a reference to generate pass and fail judgments for the other resistors.




Other electronic components


Thermistors and resettable fuses

Thermistors are characterized by a resistance value that changes in response to temperature variations. Drawing on this characteristic, thermistors are primarily used as temperature sensors.

Resistance Meters



RM3545-02
Resistance measurement range: 0.00000 mΩ to 1200.0 MΩ
Measurement current: 1 A DC to 100 nA DC



Z3003
4-terminal measurement: 10 ch
2-terminal measurement: 21 ch


Generating pass and fail judgments without temperature compensation

When used with the Z3003 Multiplexer Unit, The RM3545-02 can use previously measured values as a master reference sample connected to channel 1 to generate pass and fail judgments based on the measurement results for subsequent channels. Since measured values for channel 1 serve as the reference values for generating those judgments, there's no need to perform temperature correction.

Varistors

When a voltage that is equal to or greater than a certain value is applied to a varistor, the varistor's resistance decreases. Drawing on this characteristic, varistors are used to protect circuits by routing electricity to the ground in the event of an abnormal voltage such as a surge voltage or static electricity.

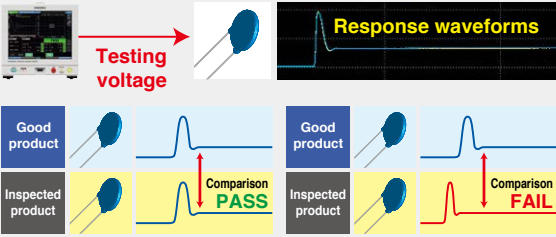
Impulse Winding Testers



ST4030A
Testing voltage: 100 V to 4200 V
Testing voltage: special specifications available for 100 V or less

Impulse testing


Impulse testers can be used to test whether a varistor functions at the defined voltage. The ST4030A can record a response waveform while applying a user-specified voltage. The response waveform from a known-good part can be used as a master/reference waveform to generate pass and fail judgments.




Piezoelectric elements

Applying pressure or vibration to a piezoelectric element generates a voltage. Conversely, applying a voltage causes the piezoelectric material to deform in shape. Drawing on this characteristic, piezoelectric elements are used in vibration sensors and actuators.

Impedance Analyzers



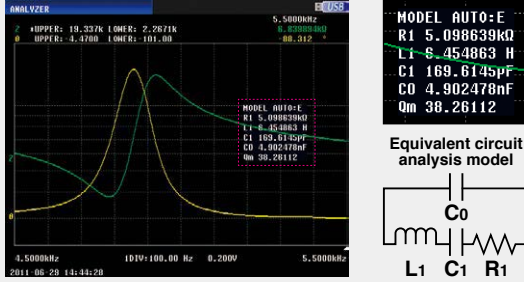
IM7580s Series



IM3570 + IM9000

Analyzing the characteristics of piezoelectric elements


The equivalent circuit analysis function can be used to analyze individual elements in an equivalent circuit model. It can also be used to calculate resonant and antiresonant frequencies.



Substrate materials

A variety of substrate materials are available. For equipment such as communications components used to exchange information at high speeds, it's essential to use substrate materials with low permittivity so that losses that occur during information transmission can be minimized.

LCR Meters



IM3536

Measuring permittivity

The IM3536 can measure permittivity if the sample's diameter and thickness are specified.

C value measured (C)

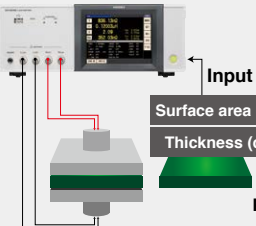
Permittivity (ε) calculated

$$C = \epsilon \left(\frac{S}{d} \right)$$

Relative permittivity calculated

$$\text{Relative permittivity} = \frac{\epsilon}{\epsilon_0}$$

Permittivity in a vacuum (ε₀) = 8.85 × 10⁻¹²



Probes and test fixtures for LCR Meters and Impedance Analyzers

For leaded components				Compatible products
1	4-TERMINAL PROBE	L2000	Cable length 1 m (3.28 ft.), DC to 8 MHz, measurable terminal diameter 0.3 to 5 mm (0.012 to 0.19 in.)	IM3533, IM3536, IM3570
2	4-TERMINAL PROBE	9140-10	Cable length 1 m (3.28 ft.), DC to 200 kHz, measurable terminal diameter 0.3 to 5 mm (0.012 to 0.19 in.)	IM3533, IM3536, IM3570
3	4-TERMINAL PROBE	9140	Cable length 1 m (3.28 ft.), DC to 100 kHz, measurable terminal diameter 0.3 to 5 mm (0.012 to 0.19 in.)	IM3533, IM3536, IM3570
4	4-TERMINAL PROBE	9500	Cable length 1 m (3.28 ft.), DC to 1 MHz, measurable terminal diameter 0.3 to 2 mm (0.012 to 0.078 in.)	IM3533, IM3536, IM3570
5	4-TERMINAL PROBE	9500-10	Cable length 1 m (3.28 ft.), DC to 200 kHz, measurable terminal diameter 0.3 to 2 mm (0.012 to 0.078 in.)	IM3533, IM3536, IM3570
6	TEST FIXTURE	9261-10	Cable length 1 m (3.28 ft.), DC to 8 MHz, measurable terminal diameter 0.3 to 1.5 mm (0.012 to 0.059 in.)	IM3533, IM3536, IM3570
7	TEST FIXTURE	9261	Cable length 1 m (3.28 ft.), DC to 5 MHz, measurable terminal diameter 0.3 to 1.5 mm (0.012 to 0.059 in.)	IM3533, IM3536, IM3570
8	TEST FIXTURE	9262	Direct connection type, DC to 8 MHz, measurable terminal diameter 0.3 to 2 mm (0.012 to 0.078 in.)	IM3533, IM3536, IM3570



L2000



9140-10



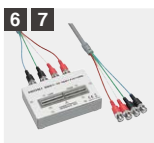
9140



9500



9500-10



9261/9261-10



9262

For surface mounting devices (SMD)				Compatible products
1	TEST FIXTURE STAND	IM9200	Use with IM9201 and IM9202	IM7580s series
2	TEST FIXTURE	IM9201	DC to 3 GHz	IM7580s series
3	TEST FIXTURE	IM9202	DC to 600 MHz	IM7580s series
4	ADAPTER	IM9906	3.5 (male) to 7 mm (0.138 to 0.276 in.) converter	IM7580s series
5	CALIBRATION KIT	IM9905	Set of OPEN, SHORT and LOAD	IM7580s series
6	SMD TEST FIXTURE	IM9110	Direct connection type, DC to 1 MHz	IM3533, IM3536, IM3570, IM7580s series
7	SMD TEST FIXTURE	IM9100	Direct connection type, DC to 8 MHz, for SMDs with electrode on bottom	IM3533, IM3536, IM3570, IM7580s series
8	SMD TEST FIXTURE	9699	Direct connection type, DC to 120 MHz, for SMDs with electrode on bottom	IM3533, IM3536, IM3570
9	SMD TEST FIXTURE	9677	Direct connection type, DC to 120 MHz, for SMDs with electrode on side	IM3533, IM3536, IM3570
10	SMD TEST FIXTURE	9263	Direct connection type, DC to 8 MHz	IM3533, IM3536, IM3570
11	PINCHER PROBE	L2001	Cable length 73 cm (28.74 in.), DC to 8 MHz, includes IM9901	IM3533, IM3536, IM3570
12	CONTACT TIPS	IM9901	For L2001 tip conversion	-
13	CONTACT TIPS	IM9902	For L2001 tip conversion	-



IM9200



IM9201



IM9202



IM9906



IM9905



IM9110



IM9100



9699



9677



9263



L2001



IM9901



IM9902

DUT size: Can the DUT size be measured?

***It may not be possible to measure depending on the shape.**

EIA (inch)	JIS (mm)	Lengths (mm)	width (mm)	IM9201	IM9202	IM9110	IM9100	9699	9677	9263	L2001 IM9901	L2001 IM9902
-	0201	0.25	0.125			Yes						
01005	0402	0.40	0.20				Yes					
0201	0603	0.60	0.30	Yes			Yes		Yes*			Yes
0402	1005	1.00	0.50	Yes			Yes		Yes			Yes
0603	1608	1.60	0.80	Yes	Yes			Yes	Yes	Yes*	Yes	Yes
0805	2012	2.00	1.25	Yes	Yes			Yes	Yes*	Yes	Yes	Yes
1206	3216	3.20	1.60	Yes	Yes			Yes*		Yes	Yes	Yes
1210	3225	3.20	2.50	Yes	Yes			Yes*		Yes	Yes	Yes
1812	4532	4.50	3.20		Yes					Yes	Yes	Yes
2220	5750	5.70	5.00		Yes					Yes	Yes	Yes

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